

January 2002 Revised January 2003

# FIN1104 LVDS 4 Port High Speed Repeater

## **General Description**

This 4 port repeater is designed for high speed interconnects utilizing Low Voltage Differential Signaling (LVDS) technology. The FIN1104 accepts and outputs LVDS levels with a typical differential output swing of 330 mV which provides low EMI at ultra low power dissipation even at high frequencies. The FIN1104 provides a V<sub>BB</sub> reference for AC coupling on the inputs. In addition the FIN1104 can directly accept LVPECL, HSTL, and SSTL-2 for translation to LVDS.

#### **Features**

- Greater than 800 Mbps data rate
- 3.3V power supply operation
- 3.5 ps maximum random jitter and 135 ps maximum deterministic jitter
- Wide rail-to-rail common mode range
- LVDS receiver inputs accept LVPECL, HSTL, and SSTL-2 directly
- Ultra low power consumption
- 20 ps typical channel-to-channel skew
- Power off protection
- > 7.5 kV HBM ESD Protection
- Meets or exceeds the TIA/EIA-644-A LVDS standard
- Available in space saving 24-Lead TSSOP package
- Open circuit fail safe protection
- V<sub>BB</sub> reference output

## **Ordering Code:**

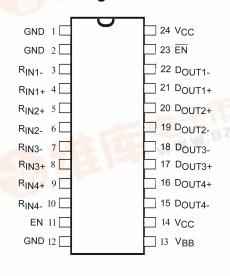
Order Number	Package Number	Package Description				
FIN1104MTC	MTC24	24-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide				

Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

### **Pin Descriptions**

Pin Name	Description		
R <sub>IN1+</sub> , R <sub>IN2+</sub> , R <sub>IN3+</sub> , R <sub>IN4+</sub>	Non-inverting LVDS Input		
R <sub>IN1-</sub> , R <sub>IN2-</sub> , R <sub>IN3-</sub> , R <sub>IN4-</sub>	Inverting LVDS Input		
D <sub>OUT1+</sub> , D <sub>OUT2+</sub> , D <sub>OUT3+</sub> , D <sub>OUT4+</sub>	Non-inverting Driver Output		
D <sub>OUT1-</sub> , D <sub>OUT2-</sub> , D <sub>OUT3-</sub> , D <sub>OUT4-</sub>	Inverting Driver Output		
EN	Driver Enable Pin for All Output		
EN	Inverting Driver Enable Pin for all Outputs		
V <sub>CC</sub>	Power Supply		
GND	Ground		
$V_{BB}$	Reference Voltage Output		

## **Connection Diagram**



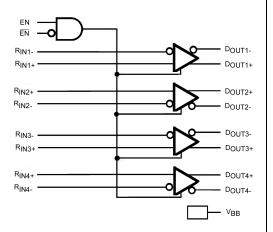


# **Function Table**

Inputs				Outputs		
EN EN		$D_{IN^+}$	$D_{IN-}$	$D_{OUT+}$	$D_{\text{OUT}-}$	
Н	L	H         L         H           L         H         L           Fail Safe Case         H		Н	L	
Н	L			Н		
Н	L			Н	L	
Х	Н	X	X	Z	Z	
L	Х	Х	Х	Z	Z	

- H = HIGH Logic Level L = LOW Logic Level X = Don't Care Z = High Impedance

# **Functional Diagram**



## **Absolute Maximum Ratings**(Note 1)

 $\begin{array}{lll} \mbox{Supply Voltage (V$_{CC}$)} & -0.5 \mbox{V to } +4.6 \mbox{V} \\ \mbox{LVDS DC Input Voltage (V$_{IN}$)} & -0.5 \mbox{V to } +4.6 \mbox{V} \\ \mbox{LVDS DC Output Voltage (V$_{OUT}$)} & -0.5 \mbox{V to } +4.6 \mbox{V} \\ \end{array}$ 

Driver Short Circuit Current ( $I_{OSD}$ )

Storage Temperature Range ( $T_{STG}$ )

-0.5v to +4.5v

Continuous 10 mA

-65°C to +150°C

Max Junction Temperature (T<sub>J</sub>) 150°C

Lead Temperature  $(T_L)$ 

 (Soldering, 10 seconds)
 260°C

 ESD (Human Body Model)
 7500V

 ESD (Machine Model)
 400V

# Recommended Operating Conditions

Supply Voltage (V<sub>CC</sub>) 3.0V to 3.6V

Magnitude of Differential

Voltage ( $|V_{ID}|$ ) 100 mV to  $V_{CC}$ 

Common Mode Voltage

 $\begin{aligned} &\text{Range (V_{IC})} & & (0\text{V} + |\text{V}_{ID}|/2) \text{ to (V}_{CC} - |\text{V}_{ID}|/2) \\ &\text{Operating Temperature (T_A)} & & -40^{\circ}\text{C to } +85^{\circ}\text{C} \end{aligned}$ 

Note 1: The "Absolute Maximum Ratings": are those values beyond which damage to the device may occur. The databook specifications should be

met, without exception, to ensure that the system design is reliable over its power supply, temperature and output/input loading variables. Fairchild does not recommend operation of circuits outside databook specification.

## **DC Electrical Characteristics**

Symbol	Parameter	Test Conditions		Min	Typ (Note 2)	Max	Units
$V_{TH}$	Differential Input Threshold HIGH	See Figure 1; $V_{IC}$ = +0.05V, +1.2V, or $V_{CC}$ - 0.05V See Figure 1; $V_{IC}$ = +0.05V, +1.2V, or $V_{CC}$ - 0.05V				100	mV
$V_{TL}$	Differential Input Threshold LOW			-100			mV
V <sub>IH</sub>	Input HIGH Voltage (EN or EN)			2.0		V <sub>CC</sub>	V
$V_{IL}$	Input LOW Voltage (EN or EN)			GND		8.0	V
V <sub>OD</sub>	Output Differential Voltage			250	330	450	mV
ΔV <sub>OD</sub>	V <sub>OD</sub> Magnitude Change from Differential LOW-to-HIGH	$R_L = 100 \Omega$ , Driver Enabled,				25	mV
Vos	Offset Voltage	See Figure 2		1.125	1.23	1.375	V
ΔV <sub>OS</sub>	Offset Magnitude Change from Differential LOW-to-HIGH					25	mV
I <sub>OS</sub>	Short Circuit Output Current	$D_{OUT+} = 0V$ and $D_{OUT-} = 0V$ , Driver Enabled			-3.4	-6	mA
		V <sub>OD</sub> = 0V, Driver Enabled			±3.4	±6	mA
I <sub>IN</sub>	Input Current (EN, $\overline{\text{EN}}$ , $D_{\text{INX+}}$ , $D_{\text{INX-}}$ )	$V_{IN} = 0V$ to $V_{CC}$ , Other Input = $V_{CC}$ or $0V$ (for Differential Inputs)				±20	μΑ
I <sub>OFF</sub>	Power Off Input or Output Current	$V_{CC} = 0V$ , $V_{IN}$ or $V_{OUT} = 0V$ to 3.6V				±20	μΑ
I <sub>CCZ</sub>	Disabled Power Supply Current	Drivers Disabled			5.4	11	mA
I <sub>CC</sub>	Power Supply Current	Drivers Enabled, Any Valid Input Conditi	on		30.4	41	mA
I <sub>OZ</sub>	Disabled Output Leakage Current	Driver Disabled, $D_{OUT+} = 0V$ to 3.6V or $D_{OUT-} = 0V$ to 3.6V				±20	μА
V <sub>IC</sub>	Common Mode Voltage Range	$ V_{ID} $ = 100 mV to $V_{CC}$		$0V +  V_{ID} /2$		V <sub>CC</sub> - ( V <sub>ID</sub>  /2)	V
C <sub>IN</sub>	Input Capacitance		able Input DS Input		2.6		pF
-	Output Capacitance	LV	Do input		2.1		nE
C <sub>OUT</sub>	Output Capacitance Output Reference Voltage	$V_{CC} = 3.3V$ , $I_{BB} = 0$ to $-275 \mu\text{A}$		1.125	1.2	1.375	pF V
V <sub>BB</sub>	Output Reference Voltage	V <sub>CC</sub> = 3.3 V, I <sub>BB</sub> = 0 t0 -275 μA		1.125	1.2	1.3/5	V

Note 2: All typical values are at  $T_A = 25^{\circ}C$  and with  $V_{CC} = 3.3V$ .

## **AC Electrical Characteristics**

Over supply voltage and operating temperature ranges, unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ (Note 3)	Max	Units
t <sub>PLHD</sub>	Differential Output Propagation Delay LOW-to-HIGH		0.75	1.1	1.75	ns
t <sub>PHLD</sub>	Differential Output Propagation Delay HIGH-to-LOW	$R_L = 100 \Omega, C_L = 5 pF,$	0.75	1.1	1.75	ns
t <sub>TLHD</sub>	Differential Output Rise Time (20% to 80%)	$V_{ID} = 200 \text{ mV to } 450 \text{ mV},$	0.29	0.4	0.58	ns
t <sub>THLD</sub>	Differential Output Fall Time (80% to 20%)	$V_{IC} =  V_{ID} /2$ to $V_{CC} - ( V_{ID} /2)$ ,	0.29	0.4	0.58	ns
t <sub>SK(P)</sub>	Pulse Skew  t <sub>PLH</sub> - t <sub>PHL</sub>	Duty Cycle = 50%,		0.02	0.2	ns
t <sub>SK(LH)</sub> ,	Channel-to-Channel Skew	See Figure 1 and Figure 3		0.02	0.15	ns
t <sub>SK(HL)</sub>	(Note 4)			0.02	0.13	113
t <sub>SK(PP)</sub>	Part-to-Part Skew (Note 5)				0.5	ns
f <sub>MAX</sub>	Maximum Frequency (Note 6)(Note 7)		400	800		MHz
t <sub>PZHD</sub>	Differential Output Enable Time from Z to HIGH	$R_L = 100 \Omega$ , $C_L = 5 pF$ ,		2.2	5	ns
t <sub>PZLD</sub>	Differential Output Enable Time from Z to LOW			2.5	5	ns
t <sub>PHZD</sub>	Differential Output Disable Time from HIGH to Z	See Figure 2 and Figure 3		1.8	5	ns
<sup>t</sup> PLZD	Differential Output Disable Time from LOW to Z			2.1	5	ns
t <sub>DJ</sub>	LVDS Data Jitter, Deterministic	$V_{ID} = 300 \text{ mV}, \text{ PRBS} = 2^{23} - 1,$ $V_{IC} = 1.2 \text{V at } 800 \text{ Mbps}$		85	135	ps
t <sub>RJ</sub>	LVDS Clock Jitter, Random (RMS)	V <sub>ID</sub> = 300 mV, V <sub>IC</sub> = 1.2V at 400 MHz		2.1	3.5	ps

Note 3: All typical values are at  $T_A = 25^{\circ}C$  and with  $V_{CC} = 3.3V$ .

Note 4:  $t_{SK(LH)}$ ,  $t_{SK(HL)}$  is the skew between specified outputs of a single device when the outputs have identical loads and are switching in the same direction.

Note 5:  $t_{SK(PP)}$  is the magnitude of the difference in propagation delay times between any specified terminals of two devices switching in the same direction (either Low-to-HIGH or HIGH-to-LOW) when both devices operate with the same supply voltage, same temperature, and have identical test circuits.

 $\textbf{Note 6:} \ Passing \ criteria \ for \ maximum \ frequency \ is \ the \ output \ V_{OD} > 200 \ mV \ and \ the \ duty \ cycle \ is \ 45\% \ to \ 55\% \ with \ all \ channels \ switching.$ 

Note 7: Output loading is transmission line environment only;  $C_L$  is < 1 pF of stray test fixture capacitance.

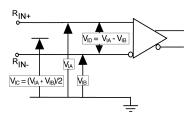


FIGURE 1. Differential Receiver Voltage Definitions and Propagation and Transition Time Test Circuit

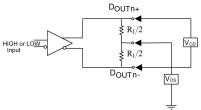
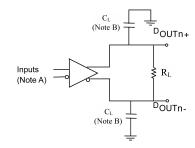


FIGURE 2. Differential Driver DC Test Circuit



Note A: All LVDS input pulses have frequency = 10 MHz,  $t_{R}$  or  $t_{F} <$  = 0.5 ns

Note B: C<sub>L</sub> includes all probe and test fixture capacitances

FIGURE 3. Differential Driver Propagation Delay and Transition Time Test Circuit

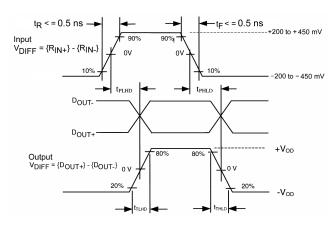
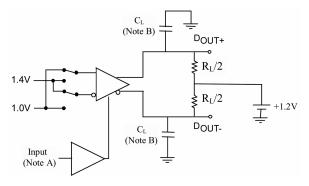


FIGURE 4. AC Waveform



Note A: All LVTTL input pulses have frequency = 10MHz,  $t_{\mbox{\scriptsize R}}$  or  $t_{\mbox{\scriptsize F}}$  < = 2 ns

Note B:  $C_L$  includes all probe and jig capacitances

#### FIGURE 5. Differential Driver Enable and Disable Circuit

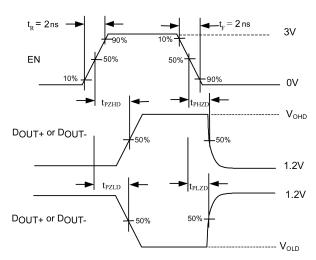
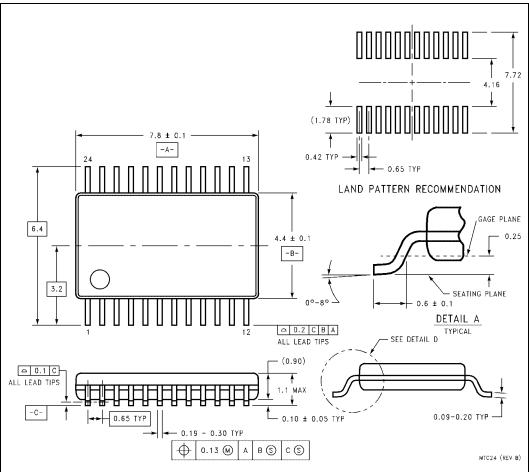


FIGURE 6. Enable and Disable AC Waveforms



24-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC24

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